



17. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

FCC ID: A3LSMJ327A	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename: 0Y1612221999-R3.A3L	Test Dates: 12/19/2016 - 12/23/2016	DUT Type: Portable Handset	Page 65 of 67	

© 2016 PCTEST Engineering Laboratory, Inc.

REV 3.1.M
11/29/2016

© 2016 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from PCTEST Engineering Laboratory, Inc. If you have any questions about this international copyright or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact INFO@PCTESTLAB.COM.



Figure 17-1
Ear Reference Point HAC Phantom Alignment

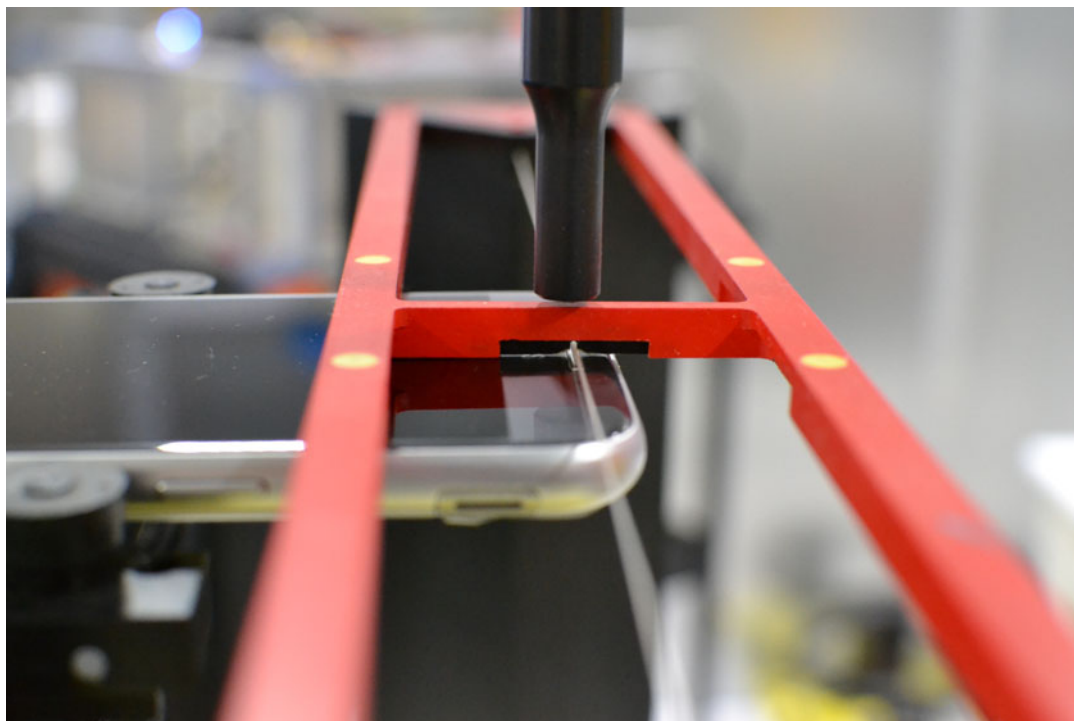




Figure 17-2
HAC Phantom Plane Alignment

FCC ID: A3LSMJ327A	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename: 0Y1612221999-R3.A3L	Test Dates: 12/19/2016 - 12/23/2016	DUT Type: Portable Handset		Page 66 of 67

© 2016 PCTEST Engineering Laboratory, Inc.

REV 3.1.M
 11/29/2016

© 2016 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from PCTEST Engineering Laboratory, Inc. If you have any questions about this international copyright or have an enquiry about obtaining additional rights to this report or assembly of contents thereof, please contact INFO@PCTESTLAB.COM.

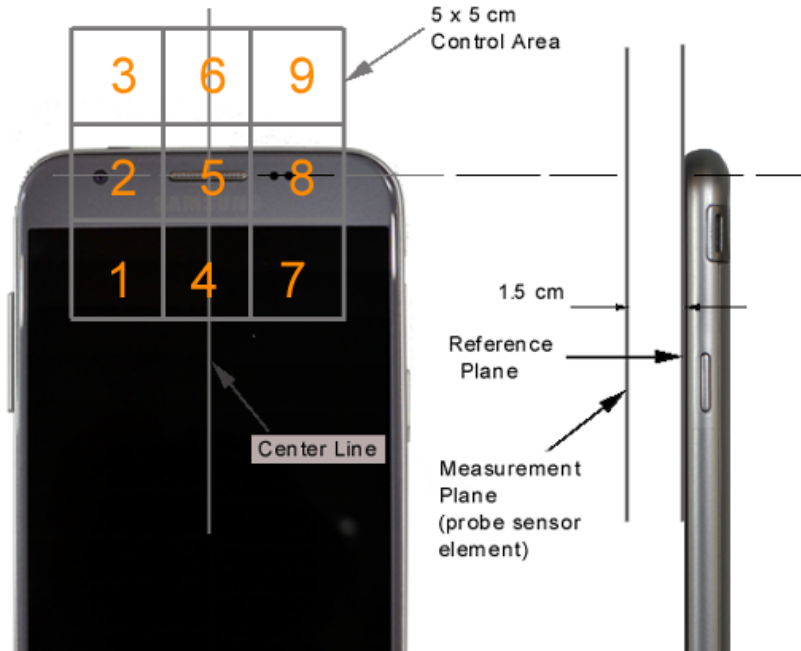


Figure 17-3 5x5 Scan grid above WD

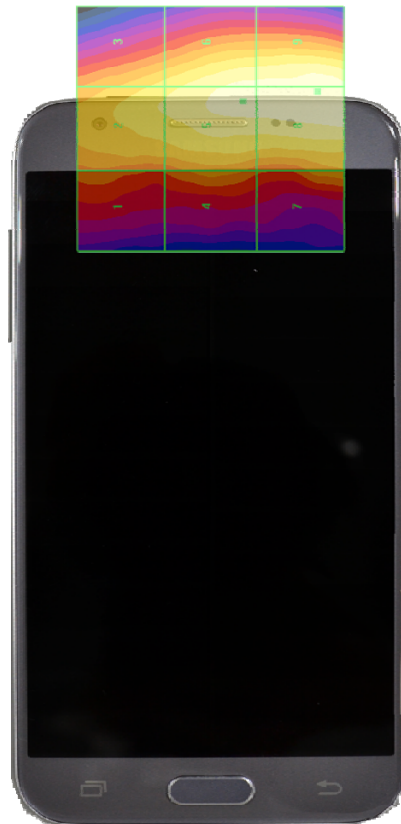




Figure 17-4 E-Field WD Scan overlay

FCC ID: A3LSMJ327A	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT	 SAMSUNG	Approved by: Quality Manager
Filename: 0Y1612221999-R3.A3L	Test Dates: 12/19/2016 - 12/23/2016	DUT Type: Portable Handset		Page 67 of 67